

30V P-Channel Enhancement Mode Power MOSFET

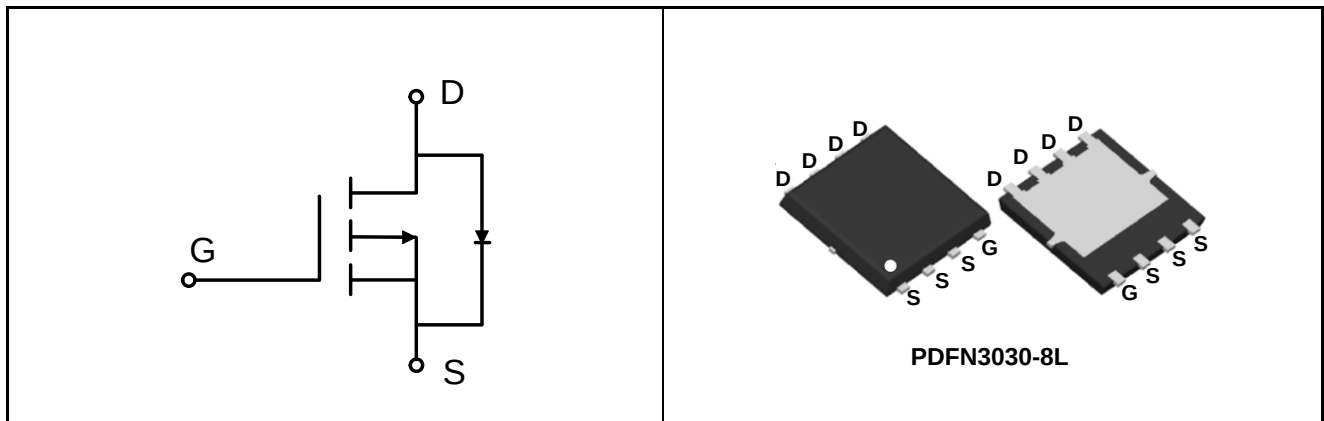
Features

- $V_{DS} = -30V$, $I_D = -42A$
 $R_{DS(on)} < 10m\Omega$ @ $V_{GS} = -10V$
 $R_{DS(on)} < 14m\Omega$ @ $V_{GS} = -4.5V$
- Green Device Available
- Low Gate Charge
- Advanced High Cell Density Trench Technology
- 100% EAS Guaranteed

Applications

- Power Management Switches
- DC/DC Converter

Schematic & PIN Configuration



EMQ42P03T1

Absolute Maximum Ratings ($T_A = 25^\circ\text{C}$, unless otherwise noted)

Parameter		Symbol	Value	Unit
Drain-Source Voltage		V_{DS}	-30	V
Gate-Source Voltage		V_{GS}	± 20	V
Continuous Drain Current	$T_C = 25^\circ\text{C}$	I_D	-42	A
	$T_C = 100^\circ\text{C}$		-27	
Pulsed Drain Current ¹		I_{DM}	-168	A
Single Pulse Avalanche Energy ²		E_{AS}	45	mJ
Total Power Dissipation	$T_C = 25^\circ\text{C}$	P_D	37	W
Operating Junction and Storage Temperature Range		T_J, T_{STG}	-55 to 150	$^\circ\text{C}$

Thermal Characteristics

Parameter	Symbol	Value	Unit
Thermal Resistance from Junction-to-Ambient ³	$R_{\theta JA}$	75	$^\circ\text{C/W}$
Thermal Resistance from Junction-to-Case	$R_{\theta JC}$	3.36	$^\circ\text{C/W}$

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Electrical Characteristics ($T_J = 25^{\circ}\text{C}$, unless otherwise noted)

Parameter		Symbol	Test Conditions	Min	Typ	Max	Unit
Static Characteristics							
Drain-Source Breakdown Voltage		$V_{(BR)DSS}$	$V_{GS} = 0V, I_D = -250\mu A$	-30	-	-	V
Gate-body Leakage current		I_{GSS}	$V_{GS} = \pm 20V, V_{DS} = 0V$	-	-	± 100	nA
Zero Gate Voltage Drain Current	$T_J=25^{\circ}C$	I_{DSS}	$V_{DS} = 30V, V_{GS} = 0V$	-	-	-1	μA
	$T_J=100^{\circ}C$			-	-	-100	
Gate-Threshold Voltage		$V_{GS(th)}$	$V_{DS} = V_{GS}, I_D = -250\mu A$	-1.0	-	-2.5	V
Drain-Source On-Resistance ⁴		$R_{DS(on)}$	$V_{GS} = -10V, I_D = -30A$	-	8	10	m Ω
			$V_{GS} = -4.5V, I_D = -15A$	-	11	14	
Forward Transconductance ⁴		g_{fs}	$V_{DS} = -5V, I_D = -30A$	-	57	-	S
Dynamic Characteristics ⁵							
Input Capacitance		C_{iss}	$V_{DS} = -15V,$ $V_{GS} = 0V,$ $f = 1MHz$	-	2396	-	pF
Output Capacitance		C_{oss}		-	325	-	
Reverse Transfer Capacitance		C_{rss}		-	283	-	
Gate Resistance		R_g	$f = 1MHz$	-	10.5	-	Ω
Switching Characteristics ⁵							
Total Gate Charge		Q_g	$V_{GS} = -10V,$ $V_{DS} = -15V,$ $I_D = -30A$	-	30	-	nC
Gate-Source Charge		Q_{gs}		-	5	-	
Gate-Drain Charge		Q_{gd}		-	7.5	-	
Turn-On Delay Time		$t_{d(on)}$	$V_{GS} = -10V, V_{DD} = -15V,$ $R_G = 3\Omega, I_D = -30A$	-	14.1	-	ns
Rise Time		t_r		-	20	-	
Turn-Off Delay Time		$t_{d(off)}$		-	94	-	
Fall Time		t_f		-	65	-	
Body Diode Reverse Recovery Time		t_{rr}	$I_F = -30A,$ $di_F/dt = -100A/\mu s$		19		ns
Body Diode Reverse Recovery Charge		Q_{rr}			9		nC
Source-Drain Body Diode Characteristics							
Diode Forward Voltage ⁴		V_{SD}	$V_{GS} = 0V, I_S = -1A$	-	-	-1.2	V
Continuous Source Current	$T_A=25^{\circ}C$	I_S	-	-	-	-42	A

Notes:

1. Repetitive rating, pulse width limited by junction temperature $T_{J(MAX)} = 150^{\circ}\text{C}$.
2. The EAS data shows Max. rating . The test condition is $V_{DD} = -25V, V_{GS} = -10V, L = 0.1\text{mH}, I_{AS} = -30A$.
3. The data tested by surface mounted on a 1 inch² FR-4 board with 2OZ copper, The value in any given application depends on the user's specific board design.
4. The data tested by pulsed , pulse width $\leq 300\mu s$, duty cycle $\leq 2\%$.
5. This value is guaranteed by design hence it is not included in the production test

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Typical Characteristics

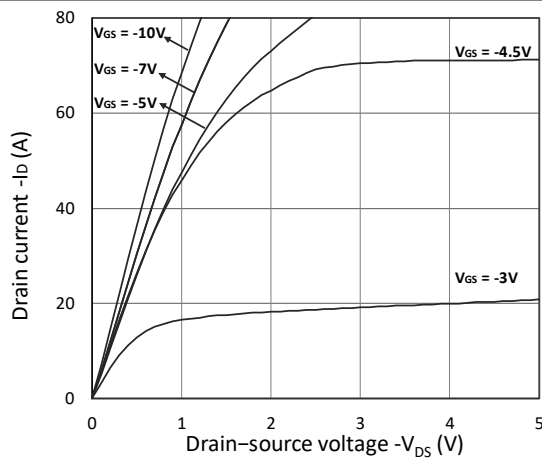


Figure 1. Output Characteristics

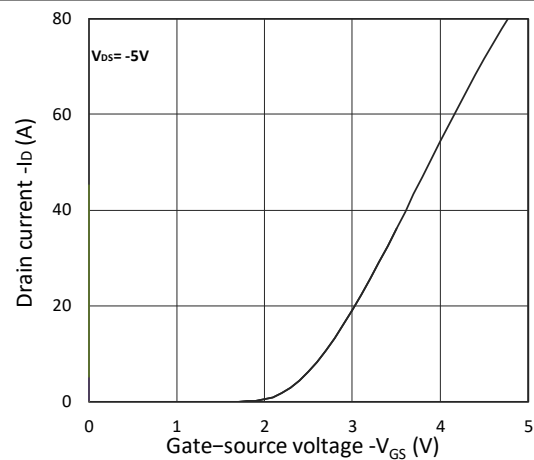


Figure 2. Transfer Characteristics

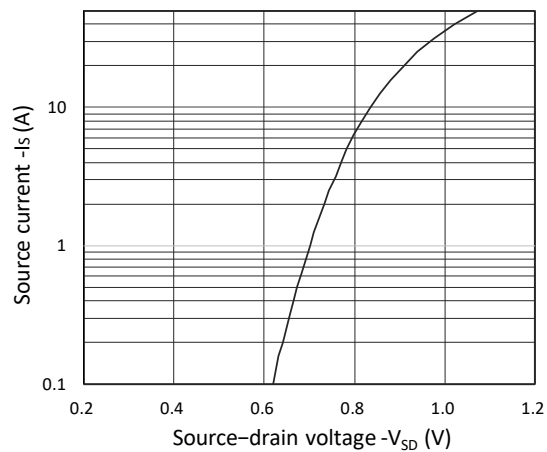


Figure 3. Forward Characteristics of Reverse

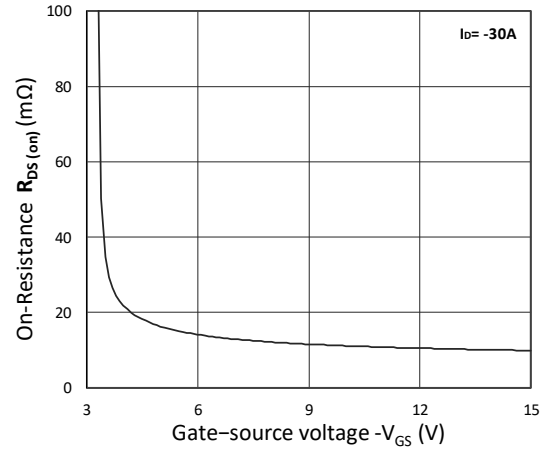


Figure 4. $R_{DS(on)}$ vs. V_{GS}

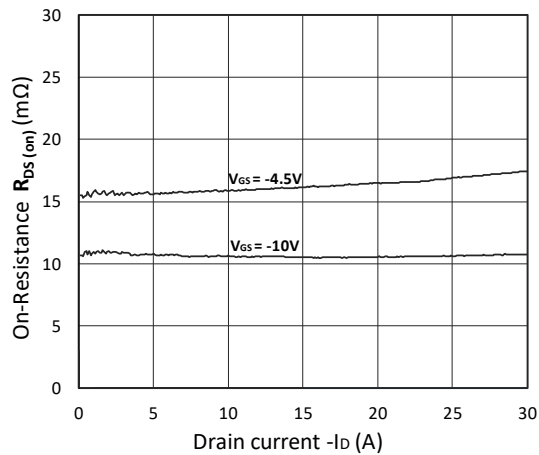


Figure 5. $R_{DS(on)}$ vs. I_D

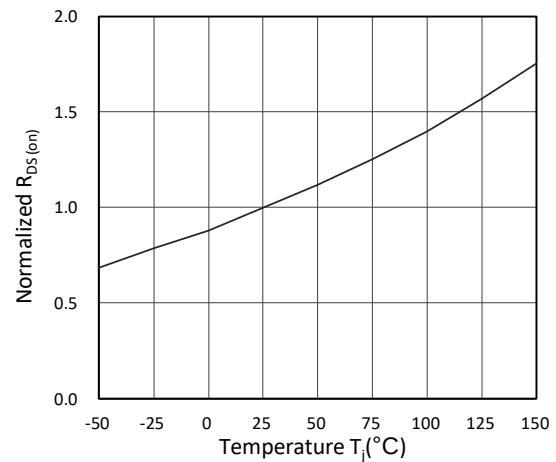


Figure 6. Normalized $R_{DS(on)}$ vs. Temperature

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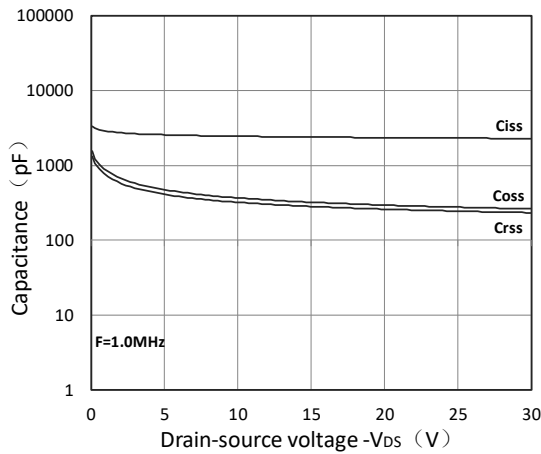


Figure 7. Capacitance Characteristics

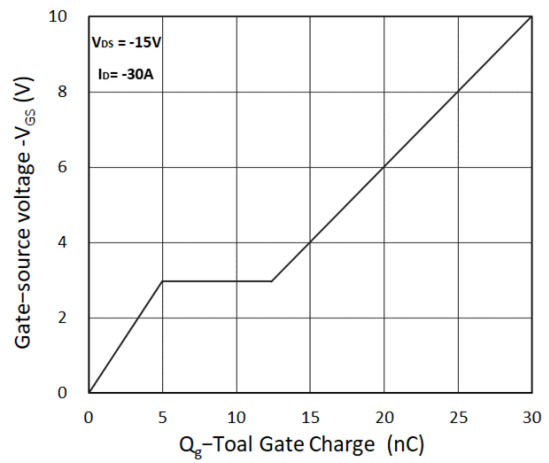


Figure 8. Gate Charge Characteristics

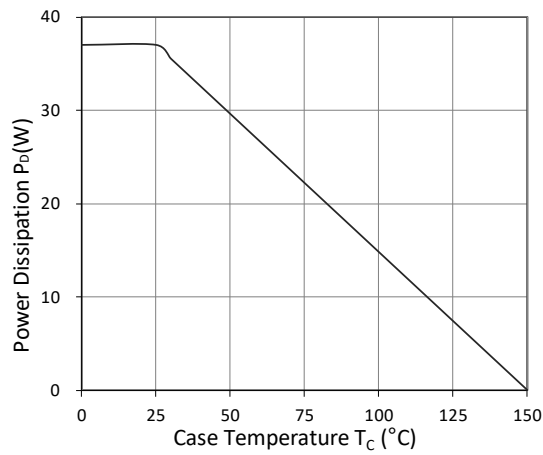


Figure 9. Power Dissipation

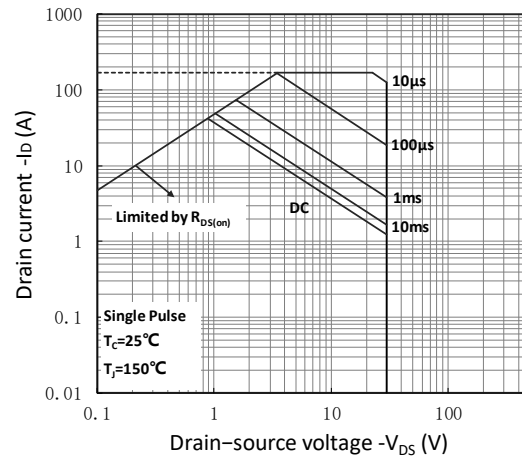


Figure10. Safe Operating Area

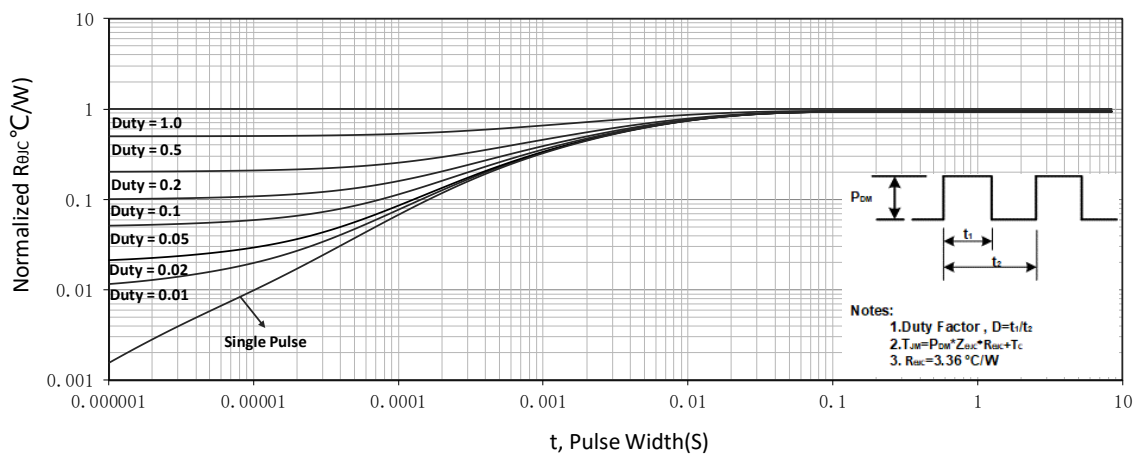


Figure 11. Normalized Maximum Transient Thermal Impedance

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Test Circuit

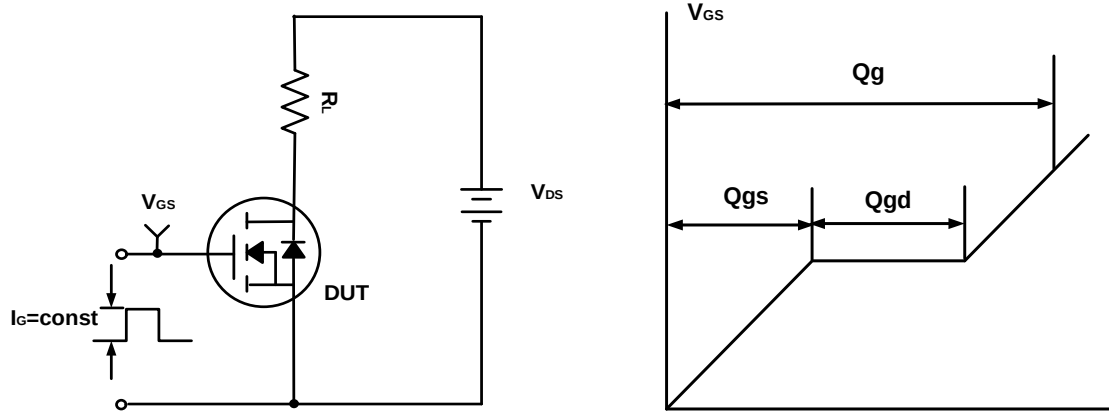


Figure A. Gate Charge Test Circuit & Waveforms

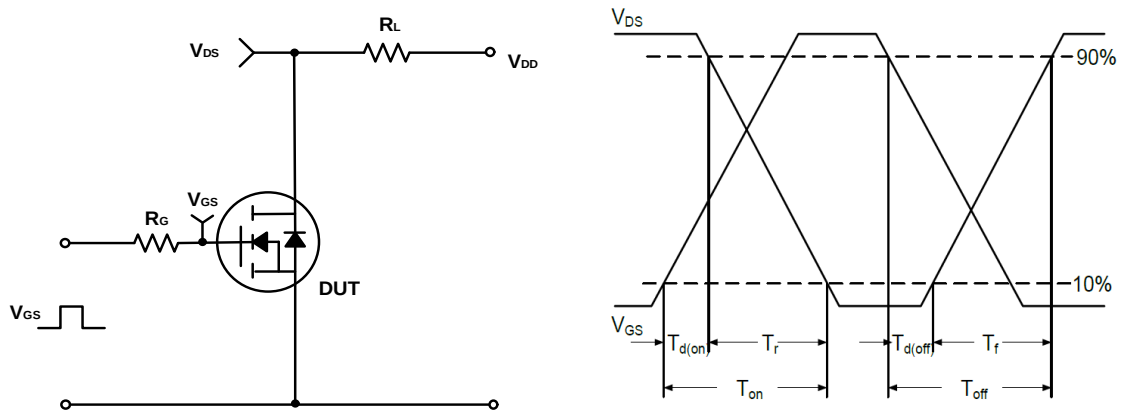


Figure B. Switching Test Circuit & Waveforms

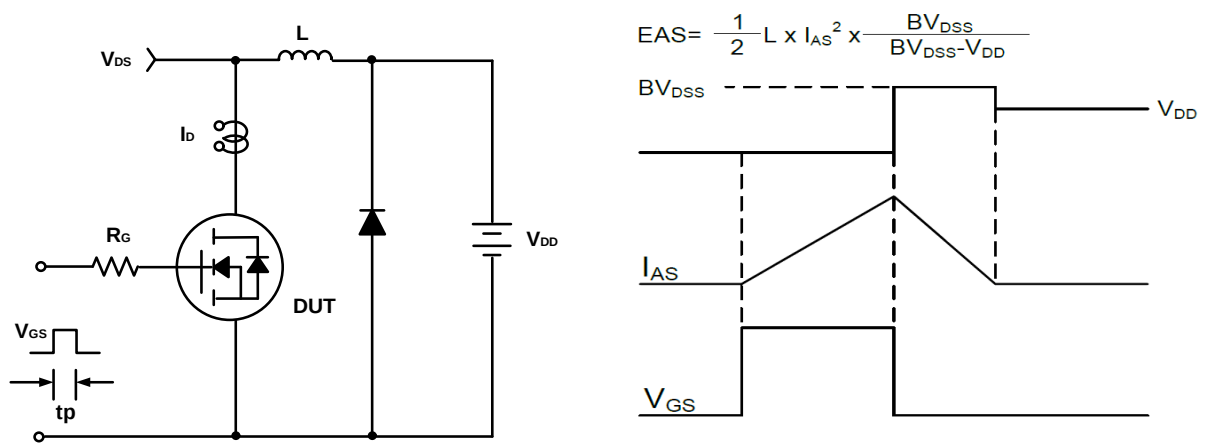
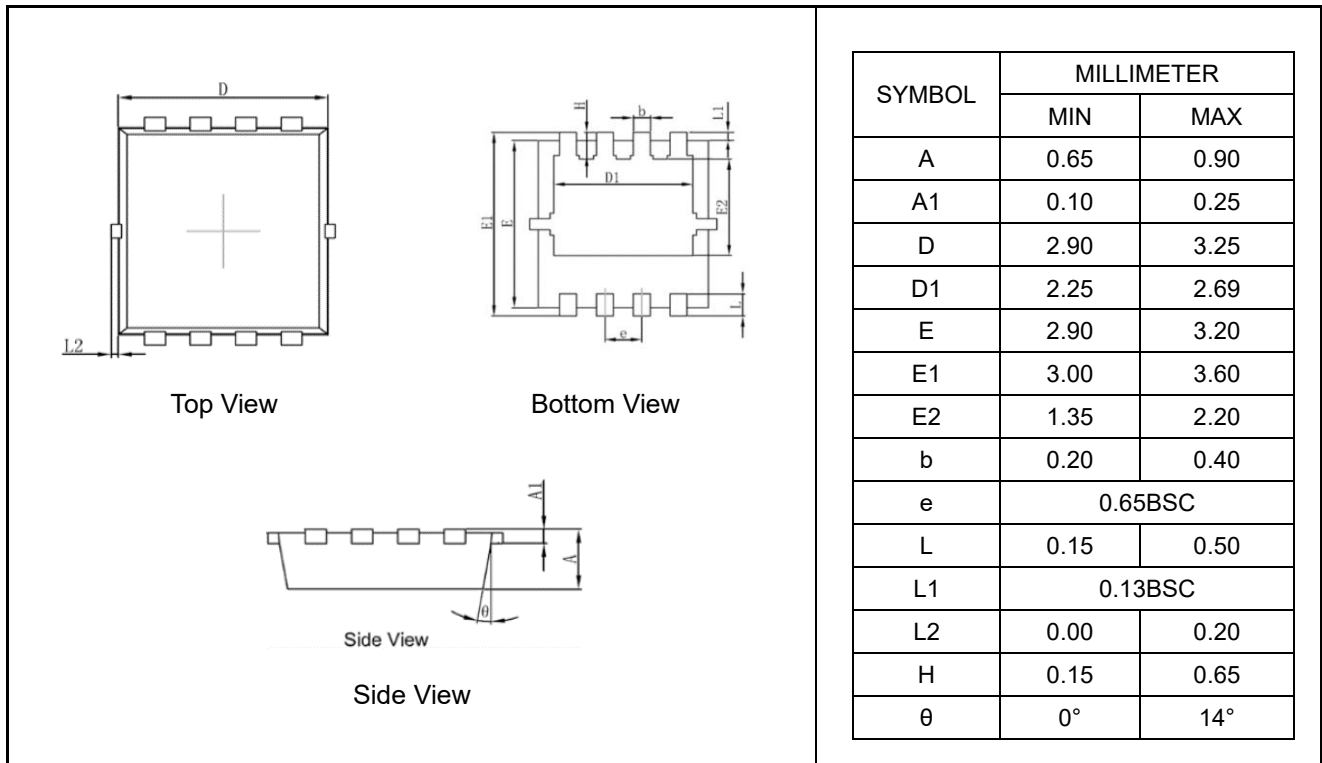


Figure C. Unclamped Inductive Switching Circuit & Waveforms

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Package Dimension

PDFN3030-8L



Revision History and Checking Table

No.	Version	Date	Revision Item	Request	Function & Spec Checking	Package Checking	Tape Checking
1	1.0	2019-07-02	Released Version	Qi Shu Kun	Qi Shu Kun	Liu Jia Ying	Liu Jia Ying